


<b>Search Notes</b>  	<b>Application/Control No.</b>  10572595	<b>Applicant(s)/Patent Under Reexamination</b>  YANO, KEIICHI
	<b>Examiner</b>  MEIYA LI	<b>Art Unit</b>  2811

SEARCHED			
Class	Subclass	Date	Examiner
257	13,79,84,98,99,E25.019,E25.032,E33.056 - E33.062,778,774,701,702	1/14,23/08	ML
438	FOR157,FOR287,FOR453,106,108	1/14,23/08	ML
313	501,512	1/14,23/08	ML

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	1/14,23/08	ML

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner